## Notice of References Cited Application/Control No. 10/781,769 Examiner David Nhu Applicant(s)/Patent Under Reexamination HON ET AL. Page 1 of 1 U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,627,921 B2	09-2003	Wong et al.	257/79
	В	US-6611003 B1	08-2003	Hatakoshi et al	257/98
	С	US-6562648 B1	05-2003	Wong et al	438/46
	D	US-5952680	09-1999	Strite	257/88
	Е	US-5281830	01-1994	Kotaki et al	257/86
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					·
	0					
	Р					
	Ø					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	W	·						
	х							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.